

<b>Notice of References Cited</b>	Application/Control No. 10/003,482	Applicant(s)/Patent Under Reexamination UR ET AL.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,373,484 B1	04-2002	Orell et al.	345/420
	B	US-5,179,702 A	01-1993	Spix et al.	718/102
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Black, P.E.; Ranville, S.;, "Winnowing tests: Getting quality coverage from a model checker without quantity", Oct. 2001, Digital Avionics Systems, 2001. DASC. The 20th Conference, Volume 2, ISBN: 0-7803-7034-1, Page(s):9B6/1 - 9B6/4
	V	Vemuri, R.; Kalyanaraman, R, "Generation of design verification tests from behavioral VHDL programs using path enumeration and constraint programming", June 1995, Very Large Scale Integration (VLSI) Systems, IEEE Transactions on□□Volume 3, Issue 2
	W	Geist et al., "Coverage-Directed Test Generation Using Symbolic Techniques", November 1996 , Proceedings of the First International Conference on Formal Methods in Computer-Aided Design, Lecture Notes In Computer Science; Vol. 1166, ISBN:3-540-61937-2
	X	Yatin Hoskote, Timothy Kam, Pei-Hsin Ho, Xudong Zhao, "Coverage estimation for symbolic model checking", June 1999, Proceedings of the 36th ACM/IEEE conference on Design automation, ISBN:1-58133-109-7, Pages: 300 - 305

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.